S-Parameters – Introduction (1)

- Light falling on a car window:
 - Some parts of the incident light is reflected (you see the mirror image)
 - Another part of the light is transmitted through the window (you can still see inside the car)
- Optical reflection and transmission coefficients of the window glass define the ratio of reflected and transmitted light
- Similar: Scattering (S-) parameters of an n-port electrical network (DUT) characterize reflected and transmitted (power) waves



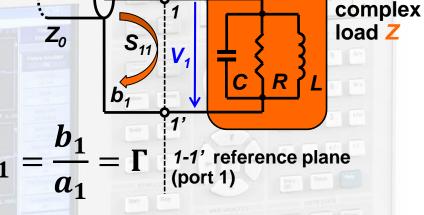
S-Parameters – Introduction (2)

Electrical networks

- 1...*n*-ports circuits
- Defined by voltages $V_n(\omega)$ or $v_n(t)$ and currents $I_n(\omega)$ or $i_n(t)$ at the ports
- Characterized by circuit matrices, e.g. ABCD (chain), Z, Y, H, etc.

RF networks

- 1...n-port RF DUT circuit or subsystem, e.g. filter, amplifier, transmission-line, hybrid, circulator, resonator, etc.
- Defined by incident $a_n(\omega, s)$ and reflected waves $b_n(\omega, s)$ at a reference plane s (physical position) at the ports
- Characterized by a scattering parameter (S-parameter) matrix of the reflected and transmitted power waves
- Normalized to a reference impedance $\sqrt{Z_0}$ of typically $Z_0 = 50 \Omega$



DUT

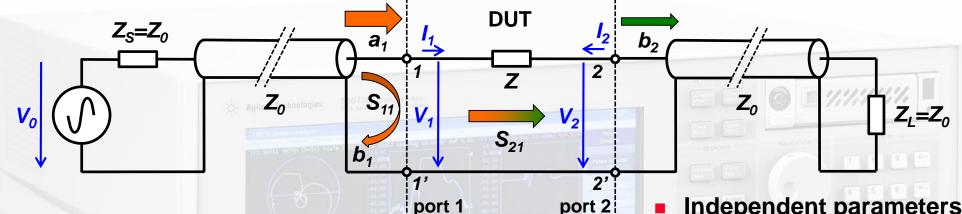
(device under test)

e.g. any

1-port DUT example

- S-Parameters allow to characterize the DUT with the measurement equipment to be located at some distance
- All high frequency effects of distributed elements are taken into account with respect to the reference plane

S-Parameters – Example: 2-port DUT



Analysis of the forward S-parameters:

$$S_{11} = \frac{b_1}{a_1}\Big|_{a_2=0}$$
 \equiv input reflection coefficient $(Z_L = Z_0 \Rightarrow a_2 = 0)$
 $S_{21} = \frac{b_2}{a_1}\Big|_{a_2=0}$ \equiv forward transmission gain

- Examples of 2-ports DUT: filters, amplifiers, attenuators, transmission-lines (cables), etc.
- ALL ports ALWAYS need to be terminated in their characteristic impedance!

Independent parameters:

$$a_{1} = \frac{V_{1}^{inc}}{\sqrt{Z_{0}}} = \frac{V_{1} + I_{1}Z_{0}}{2\sqrt{Z_{0}}}$$

$$a_{2} = \frac{V_{2}^{inc}}{\sqrt{Z_{0}}} = \frac{V_{2} + I_{2}Z_{0}}{2\sqrt{Z_{0}}}$$

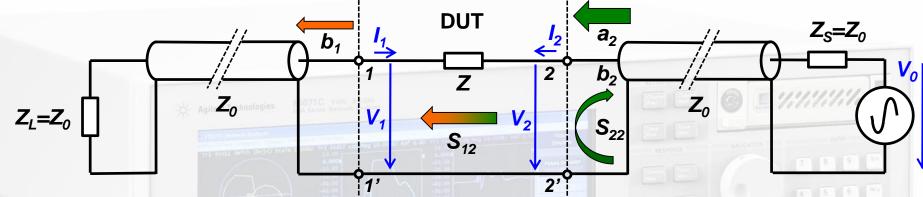
Dependent parameters:

$$b_{1} = \frac{V_{1}^{refl}}{\sqrt{Z_{0}}} = \frac{V_{1} - I_{1}Z_{0}}{2\sqrt{Z_{0}}}$$

$$b_{2} = \frac{V_{2}^{refl}}{\sqrt{Z_{0}}} = \frac{V_{2} - I_{2}Z_{0}}{2\sqrt{Z_{0}}}$$

S-Parameters – Example: 2-port DUT

port 1



port 2

Analysis of the reverse S-parameters:

$$S_{22} = \frac{b_2}{a_2}\Big|_{a_1=0}$$
 \equiv output reflection coefficient $(Z_L = Z_0 \Rightarrow a_1 = 0)$
 $S_{12} = \frac{b_1}{a_2}\Big|_{a_1=0}$ \equiv backward transmission gain

n-port DUTs still can be fully characterized with a 2-port VNA, but again: don't forget to terminate unused ports! Independent parameters:

$$a_{1} = \frac{V_{1}^{inc}}{\sqrt{Z_{0}}} = \frac{V_{1} + I_{1}Z_{0}}{2\sqrt{Z_{0}}}$$

$$a_{2} = \frac{V_{2}^{inc}}{\sqrt{Z_{0}}} = \frac{V_{2} + I_{2}Z_{0}}{2\sqrt{Z_{0}}}$$

Dependent parameters:

$$b_{1} = \frac{V_{1}^{refl}}{\sqrt{Z_{0}}} = \frac{V_{1} - I_{1}Z_{0}}{2\sqrt{Z_{0}}}$$

$$b_{2} = \frac{V_{2}^{refl}}{\sqrt{Z_{0}}} = \frac{V_{2} - I_{2}Z_{0}}{2\sqrt{Z_{0}}}$$

S-Parameters – Definition (1)

Linear equations for the 2-port DUT:

with:
$$S_{11} = \frac{b_1}{a_1} \Big|_{a_2=0} \equiv \text{input reflection coefficient}$$

$$S_{22} = \frac{b_2}{a_2} \Big|_{a_1=0} \equiv \text{output reflection coefficient}$$

$$S_{21} = \frac{b_2}{a_1} \Big|_{a_2=0} \equiv \text{forward transmission gain}$$

$$S_{12} = \frac{b_1}{a_2} \Big|_{a_1=0} \equiv \text{backward transmission gain}$$

S-Parameters – Definition (2)

Reflection coefficient and impedance at the nth-port of a DUT:

$$S_{nn} = \frac{b_n}{a_n} = \frac{\frac{V_n}{I_n} - Z_0}{\frac{V_n}{I_n} + Z_0} = \frac{Z_n - Z_0}{Z_n + Z_0} = \Gamma_n$$

$$Z_n = Z_0 rac{1 + S_{nn}}{1 - S_{nn}}$$
 with $Z_n = rac{V_n}{I_n}$ being the input impedance at the n^{th} port

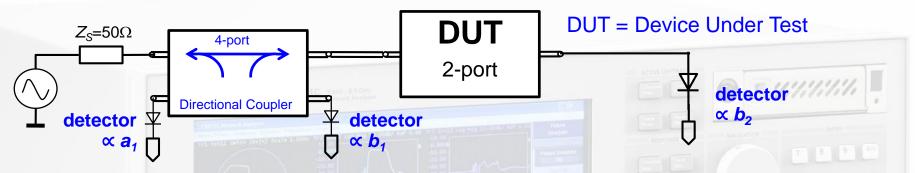
Power reflection and transmission for a n-port DUT

$$|S_{nn}|^2 = \frac{\text{power reflected from port } n}{\text{power incident on port } n}$$

$$|S_{nm}|^2 = {
m transmitted\ power\ between\ ports\ } n {
m\ and\ } m$$
 with all ports terminated in their characteristic impedance Z_0 and $Z_S = Z_0$ Here the US notion is used, where power = $|a|^2$.

European notation (often): power = $|a|^2/2$ These conventions have no impact on the S-parameters, they are only relevant for absolute power calculations

How to measure S-Parameters?



- Performed in the frequency domain
 - Single or swept frequency generator, stand-alone or as part of a VNA or SA
 - Requires a directional coupler and RF detector(s) or receiver(s)
- Evaluate S_{11} and S_{21} of a 2-port DUT
 - Ensure a_2 =0, i.e. the detector at port 2 offers a well matched impedance
 - Measure incident wave a1 and reflected wave b1 at the directional coupler ports and compute for each frequency
 - Measure transmitted wave b₂ at DUT port 2 and compute

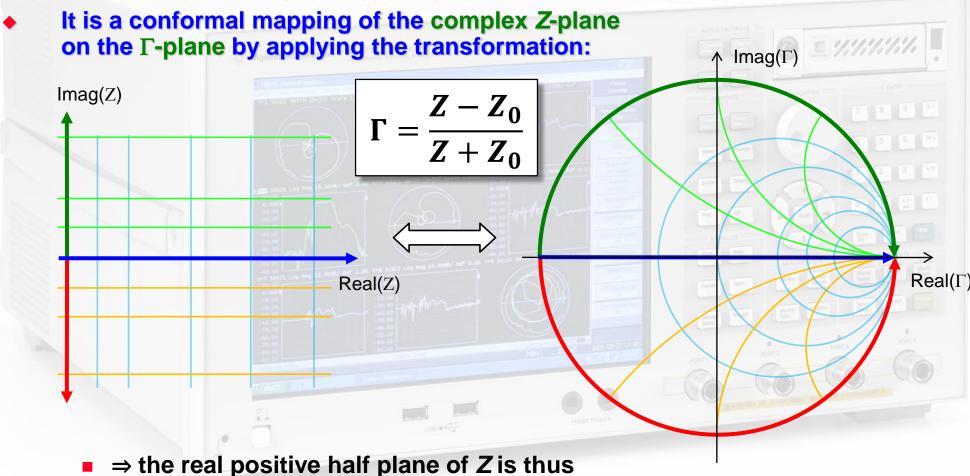
$$S_{11} = \frac{b_1}{a_1} \bigg|_{a_2 = 0}$$

$$S_{21} = \frac{b_2}{a_1} \bigg|_{a_2 = 0}$$

- Evaluate S_{22} and S_{12} of the 2-port DUT
 - Perform the same methodology as above by exchanging the measurement equipment on the DUT ports

The Smith Chart (1)

The Smith Chart (in impedance coordinates)
 represents the complex Γ-plane (in polar coordinates) within the unit circle.



transformed (Möbius) into the interior of the unit circle!

The Smith Chart (2)

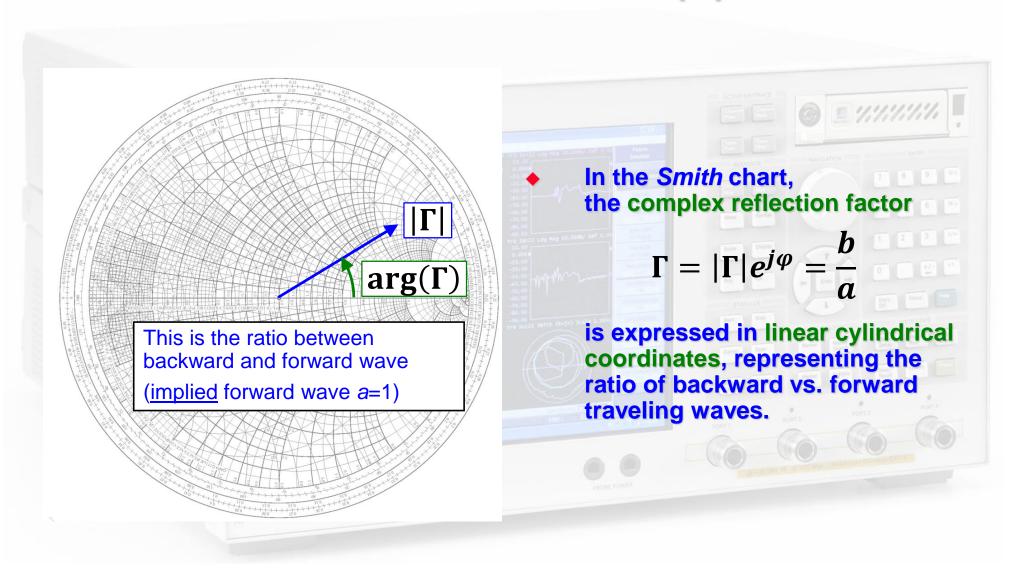
- The Impedance Z is usually normalized $z = \frac{Z}{Z_0}$ to a reference impedance Z_0 , typically the characteristic impedance of the coaxial cables of Z_0 =50Ω.
- The normalized form of the transformation follows then as:

$$\Gamma = \frac{z-1}{z+1}$$
 resp. $\frac{Z}{Z_0} = z = \frac{1+\Gamma}{1-\Gamma}$

This mapping offers several practical advantages:

- The diagram includes all "passive" impedances, i.e. those with positive real part, from zero to infinity in a handy format.
 - Impedances with negative real part ("active device", e.g. reflection amplifiers) would be outside the (normal) Smith chart.
- The mapping converts impedances or admittances into reflection factors and vice-versa. This is particularly interesting for studies in the radiofrequency and microwave domain where electrical quantities are usually expressed in terms of "incident" or "forward", and "reflected" or "backward" waves.
 - This replaces the notation in terms of currents and voltages used at lower frequencies.
- Also the reference plane can be moved very easily using the Smith chart.

The Smith Chart (3)

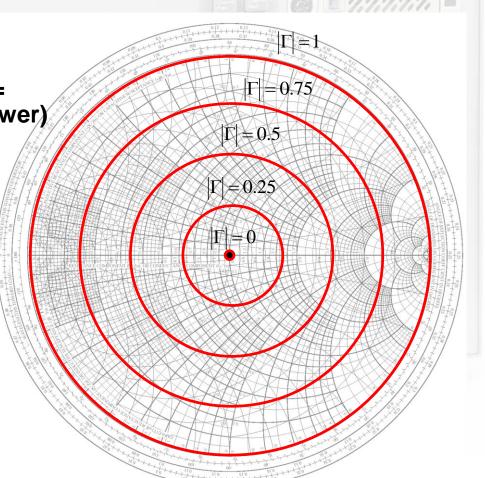


The Smith Chart (4)

- The distance from the center of the directly proportional to the magnitude of the reflection factor |Γ|, and permits an easy visualization of the matching performance.
 - In particular, the perimeter of the diagram represents total reflection: |Γ|=1.
 - (power dissipated in the load) = (forward power) – (reflected power)

$$P = |a|^2 - |b|^2$$

$$= |a|^2 (1 - |\Gamma|^2)$$
available mismatch losses



The Smith Chart – "Important Points"

